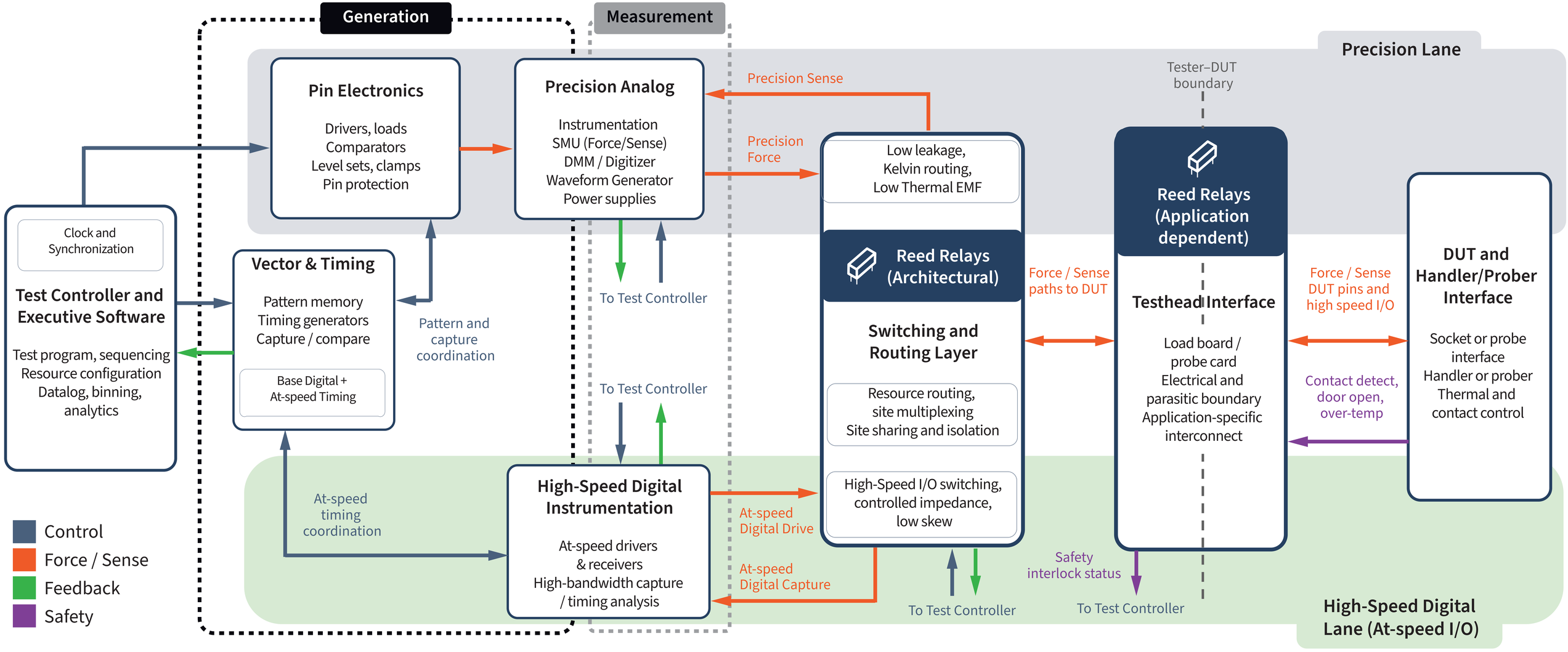
Generation
Measurement
Precision Lane
Pin Electronics
Drivers, loads
Comparators
Level sets, clamps
Pin protection
Precision Analog
Instrumentation
SMU (Force/Sense)
DMM / Digitizer
Waveform Generator
Power supplies
Precision Sense
Precision Force
Tester–DUT boundary
Clock and Synchronization
Test Controller and Executive Software
Test program, sequencing
Resource configuration
Datalog, binning, analytics
Vector & Timing
Pattern memory
Timing generators
Capture / compare
Base Digital + At-speed Timing
Pattern and capture coordination
To Test Controller
To Test Controller
Low leakage, Kelvin routing, Low Thermal EMF
Reed Relays (Architectural)
Switching and Routing Layer
Resource routing, site multiplexing
Site sharing and isolation
High-Speed I/O switching, controlled impedance, low skew
Force / Sense paths to DUT
Reed Relays (Application dependent)
Testhead Interface
Load board / probe card
Electrical and parasitic boundary
Application-specific interconnect
Force / Sense DUT pins and high speed I/O
Contact detect, door open, over-temp
DUT and Handler/Prober Interface
Socket or probe interface
Handler or prober
Thermal and contact control
At-speed timing coordination
High-Speed Digital Instrumentation
At-speed drivers & receivers
High-bandwidth capture / timing analysis
At-speed Digital Drive
At-speed Digital Capture
To Test Controller
Safety interlock status
To Test Controller
High-Speed Digital Lane (At-speed I/O)
Control
Force / Sense
Feedback
Safety